

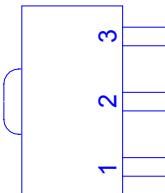
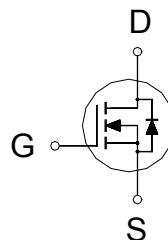
NIKO-SEM
**N-Channel Logic Level Enhancement
Mode Field Effect Transistor**
P3057LCG

SOT-89

Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
25	50m Ω	6A



1. GATE
2. DRAIN
3. SOURCE

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ABSOLUTE MAXIMUM RATINGS ($T_c = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	6	A
		4	
Pulsed Drain Current ¹	I_{DM}	20	
Power Dissipation	P_D	3	W
		1.2	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C
Lead Temperature (1/16" from case for 10 sec.)	T_L	275	

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		18	
Junction-to-Ambient	$R_{\theta JA}$		160	°C / W

¹Pulse width limited by maximum junction temperature.²Duty cycle ≤ 1%**ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	25			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.8	1.2	2.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20V, V_{GS} = 0V$			25	μA
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			250	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10V, V_{GS} = 10V$	6			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 4.5V, I_D = 3A$		70	115	$\text{m}\Omega$
		$V_{GS} = 10V, I_D = 6A$		48	85	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 15V, I_D = 6A$		16		S

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DYNAMIC

Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$	450		pF
Output Capacitance	C_{oss}		200		
Reverse Transfer Capacitance	C_{rss}		60		
Total Gate Charge ²	Q_g	$V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = 10V,$ $I_D = 6A$	15		nC
Gate-Source Charge ²	Q_{gs}		2.0		
Gate-Drain Charge ²	Q_{gd}		7.0		
Turn-On Delay Time ²	$t_{d(on)}$		6.0		nS
Rise Time ²	t_r		6.0		
Turn-Off Delay Time ²	$t_{d(off)}$		20		
Fall Time ²	t_f		5.0		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25^{\circ}\text{C}$)					
Continuous Current	I_S			2.3	A
Pulsed Current ³	I_{SM}			4	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{GS} = 0V$		1.5	V

¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.**REMARK: THE PRODUCT MARKED WITH "P3057G", DATE CODE or LOT #**

Orders for parts with Lead-Free plating can be placed using the PXXXXXXG parts name.

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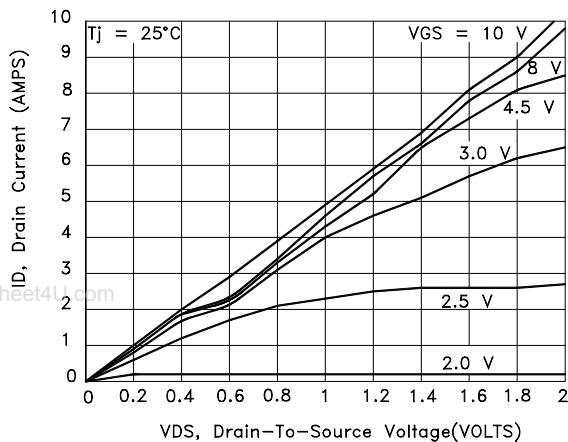


Fig.1 On-Resistance Variation with Temperature

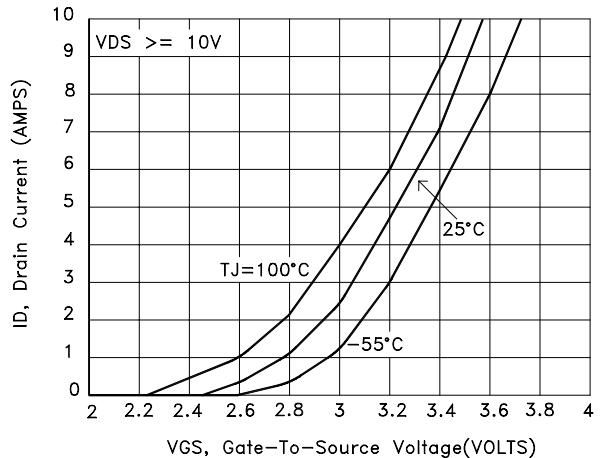


Fig.2 Transfer Characteristics

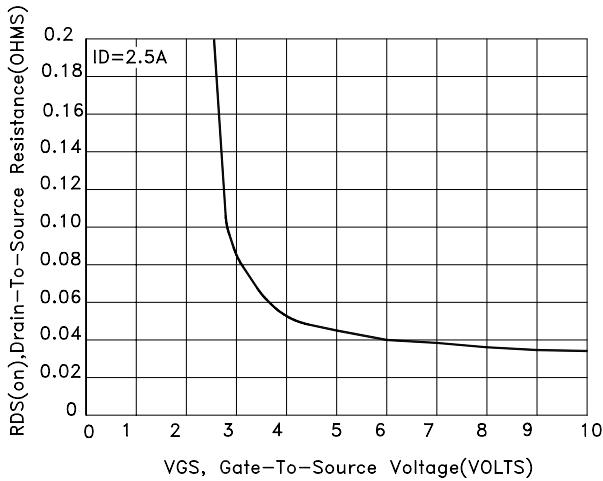


Fig.3 On-Resistance versus Gate-To-Source Voltage

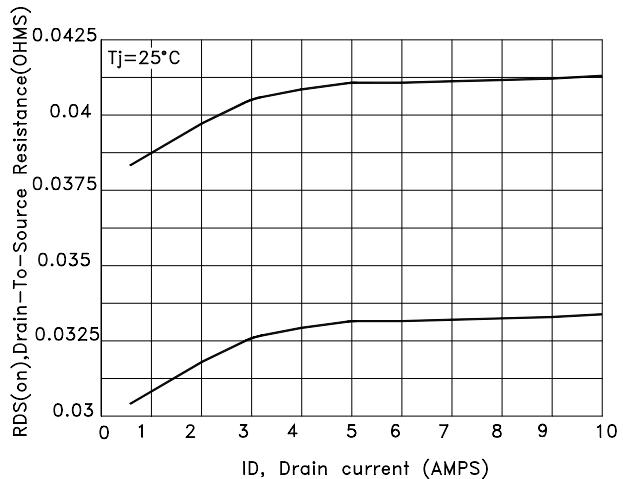


Fig.4 On-Resistance versus Drain Current and Gate Voltage

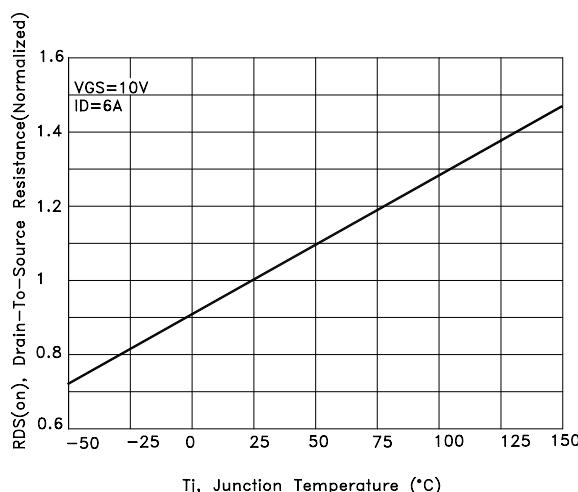


Fig.5 On-Resistance Variation with Temperature

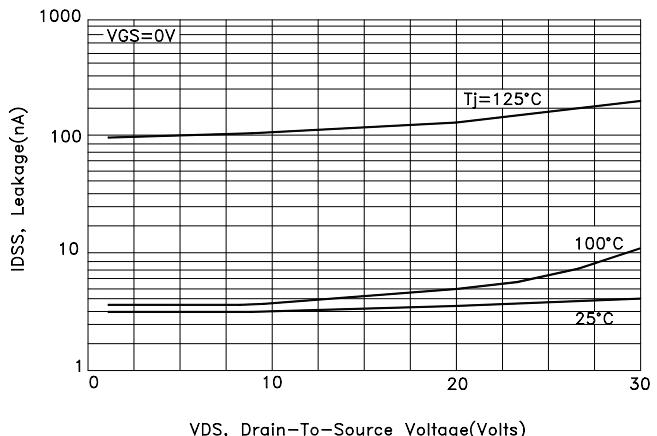


Fig.6 Drain-To-Source Leakage Current versus Voltage

SOT-89 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.3	4.5	4.7	H	1.4	1.5	1.6
B	1.6	1.7	1.8	I	2.8	3.0	3.2
C	0.4	0.5	0.6	J	1.3	1.5	1.7
D	2.4	2.5	2.6	K	3.8	4.2	4.6
E	0.8	1.2	1.4	L	0.3	0.4	0.5
F	0.4	0.45	0.5	M			
G	0.4	0.5	0.6	N			

